

DIGITAL MULTIMETERS FOR HOBBYISTS

# Popular Electronics®

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**NEW, PRACTICAL  
OP AMP CIRCUITS**

includes a differential  
PC board tester

**HOW TO ADD  
DIGITAL FREQUENCY  
READOUT TO  
SHORTWAVE RECEIVERS**

**TEST REPORTS:**

Pioneer CT-F8282 Stereo Cassette Deck  
Acoustic Research AR-16 Speaker System

## BUILD A LOW-COST LOGIC ANALYZER

Data-domain instrument for troubleshooting  
microcomputers and other digital equipment



Retailers: Notice of display-allowance plan is within last three pages.

Digital circuitry has spawned a variety of troubleshooting aids, including logic probes, pulse generators, IC clip-type testers, logic comparators, and multiple-trace oscilloscopes. All are most useful—up to a point. That point is reached when the digital equipment contains a microprocessor, as in computers, scanning monitors, video games, microwave ovens, etc.


In such cases, how does one examine a number of operating interdependent circuit lines for debugging purposes? Industry knows how—with a "logic analyzer," an instrument with a bottom price of about \$2500. Now, however, you can build your own logic analyzer for less than \$190.

The Logic Analyzer presented here features eight input lines and an ability to examine sequential data before or after a reference event, displaying a truth table consisting of 1's and 0's on any oscilloscope CRT. This is called a data-domain logic analyzer. (There are, of course, other types of analyzers, one of which displays a timing diagram on a scope's CRT.)

**Why a Logic Analyzer?** Because digital logic operates at two different voltage levels (0's and 1's), the first special-digital test instrument was the simple digital probe. The digital probe uses some type of indicator, usually a LED, to indicate the presence or absence of a signal at any selected single point in a circuit. Since digital circuits usually consist of a number of IC's that all operate from a common timing clock, even if a single digital probe gives a proper indication at a given test point, there is no way of determining if the observed pulse is correctly timed.

The shortcomings of the digital probe led to the development of the IC "clip" tester in which 14 or 16 LED's could indicate the logic states at each of the IC pins. Note that the status of the logic is of interest only at a specified instant in time related to the clock. This brings up another problem—clock speed. With most clock rates, single 14/16-pin LED indicator probes may display only a blur (except at the ground and power pins of the IC), with the blur rate, or light intensity, a function of the clock speed. Hence, unless you are able to drastically slow down the clock rate, you still will not be able to discover anything but the presence or absence of signals, whether or not they are correctly timed.

Using a logic analyzer with an oscilloscope, you can display a "truth table" of the digital circuit being tested under ac-



**BREAKTHROUGH PROJECT**

# Low-Cost Digital Logic Analyzer

*Data-domain instrument for troubleshooting any type of digital system including microcomputers.*

BY G. MUETHING, I. SPECTOR, AND C. WONG

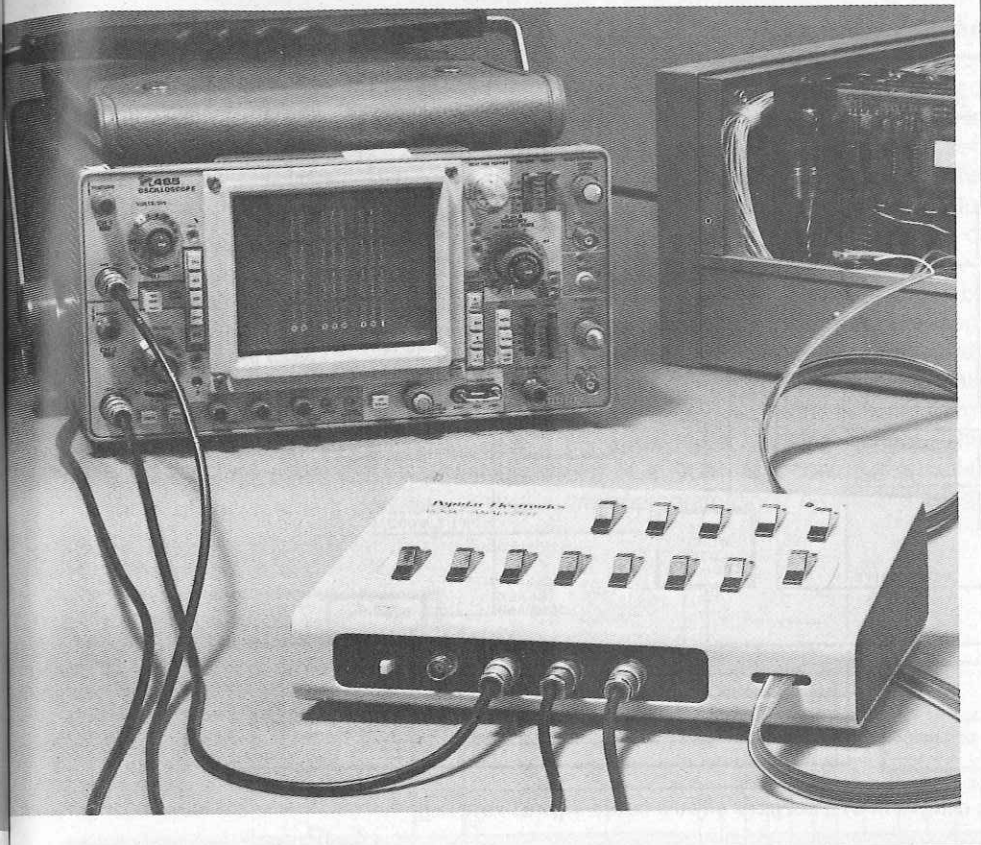
tual operating conditions. Simply by selecting a "trigger word" consisting of a particular set of 1's and 0's, the analyzer will freeze the 15 8-bit digital words that precede the selected trigger word and display the data so that it can be analyzed at your leisure. A switch also allows the observation of the 15 digital words that follow the trigger word if the problem is thought to lie in that direction. By changing the trigger word, which is brightness accented in the display, as you step through the truth table, it becomes possible to examine the digital logic from start to finish. In essence, then, the Logic Analyzer is a form of electronic "time machine" that can freeze digital events before or after any selected point in time.

Because a computer consists of a number of interlocking digital circuits, each carefully timed from a common clock signal, the misplacement of one bit among thousands can cause a great deal of trouble. Programs that can be properly written will not run because of an erroneous bit being generated within the system.

Why not use a conventional oscilloscope? True, you can see a small group of bits at any given time. But if the system under test is running at the usual clock rates, the picture displayed will

keep changing and be blurred. The scope can display a signal only after it has been triggered. If you happen to trigger on the problem itself, you have further complications. Because computers, peripherals, ROM's, and other digital devices may not repeat the same state over and over again, a scope without storage capability cannot display a "snapshot" of a one-time logic event for subsequent analysis. In some cases, the scope is a necessity, as only a scope can display the detailed waveform information that can give the user an insight by an intuitive process where a waveform "just doesn't look right". A good scope can also show up fast transient "glitches" that, although they disturb circuit operation, may not show up on an analyzer. However, if you rely strictly on a scope for analysis, solving many system problems would be virtually impossible.

The low-cost Logic Analyzer in this article will add a form of storage to any oscilloscope, perform the sixteen 8-bit data word freeze as previously described, and provide the electronics experimenter with a state-of-the-art digital test instrument that rivals those costing several hundred dollars more. In use, you simply connect the three analyzer outputs to the horizontal, vertical, and



blanking inputs of a scope and connect the eight data-input and the clock and ground probes to the circuit being analyzed. When the trigger word keyed in via control-panel switches appears, the Analyzer will automatically trigger, collect, store, and display 16 sequential 8-bit words in either octal or hex format, as shown in Fig. 1. The analyzer will accept data rates as high as 8-million bytes/second.

Another front-panel control allows the user to select either "positive time" in which the selected trigger word appears intensified on the top of the CRT screen with the next 15 sequential data words below it, or "negative time" in which the 15 data words leading up to the trigger word appear first with the brightened trigger word at the bottom of the screen.

One other control provides the choice of a "snapshot" that catches and displays an individual 16-word table for as long as you like or a "moving picture" display in which the data for each table is collected and automatically displayed so you can dynamically observe the operation of the circuit. The specifications for the logic analyzer are shown in the box.

**Circuit Operation.** Operation of the analyzer can best be understood by ref-

erring to the block diagram of Fig. 2. (The complete schematic diagram is shown in sections in Figs. 3 through 7.) The inputs to the system are the 8-bit signals (BIT 0 through BIT 7), the system clock, and the common or ground bus of the digital circuit under test. The data and clock inputs are buffered by IC1 and IC2. The eight data signals are latched by IC4 and IC5 before loading into data memory IC6 and IC7. This 16-word data memory is the "heart" of the analyzer. It stores sequential data words from the digital system under test.

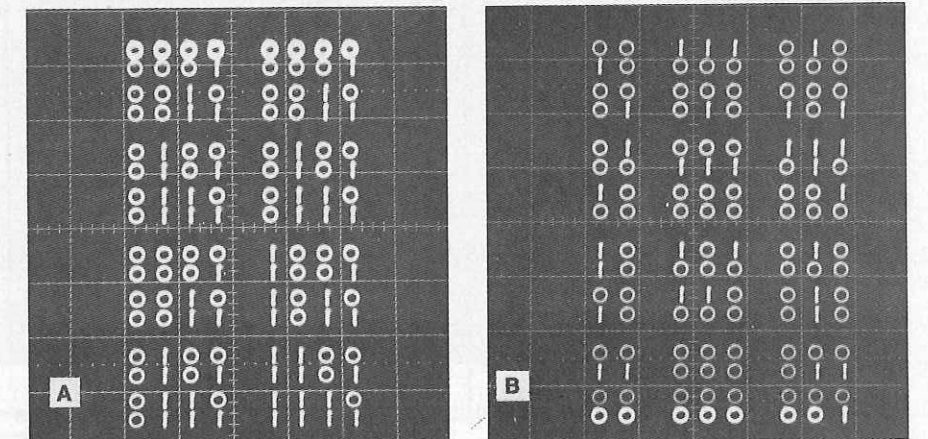


Fig. 1. Trigger word is intensified at top of hex display (A) with the 15 following data words. In octal display (B), trigger word is at bottom with the 15 data words leading up to it.

The buffered clock signal is fed to half of IC2 that can be set to operate on either the negative or positive edge, depending on the setting of S10. This signal is applied to the display control logic made up of IC11 through IC15. The other input to the display logic is from comparator IC3. This circuit uses S1 through S8 to set up the desired trigger word, with the switches set to either 1, 0, or X as required. (The X is a "don't care" state.) When the comparator receives the input data word that matches its switches, a signal is passed to the display control logic. When S11 is set to the POS TIME position, for example, data collection begins when the comparator detects the trigger word. After 16 clock pulses, data collection stops so that the memory contains the trigger word followed by the next 15 data words. In the NEG TIME position of S11, the memory stores data continuously until the trigger word occurs. When this happens, data collection is halted, leaving the memory with the 15 data words leading up to the trigger, plus the trigger word itself.

During the data collection period, the display control logic sends a signal to the blanking logic system made up of IC22 through IC24, Q1, and Q2 to inhibit the display. At the end of this period, the blanking signal is removed and a bit-by-bit scan of the memory contents is initiated. Scanning is accomplished by data multiplexer IC16, which is controlled by three of the eight output bits of horizontal control ROM IC19. Thus, even though the data memory provides a full 8-bit wide data word to the input of the multiplexer, only one bit at a time is sent to the 1-0 character generator made up of half of IC20, and Q3.

The character generator uses this information and the CRT beam positioning signals from the IC20 horizontal D/A (di-

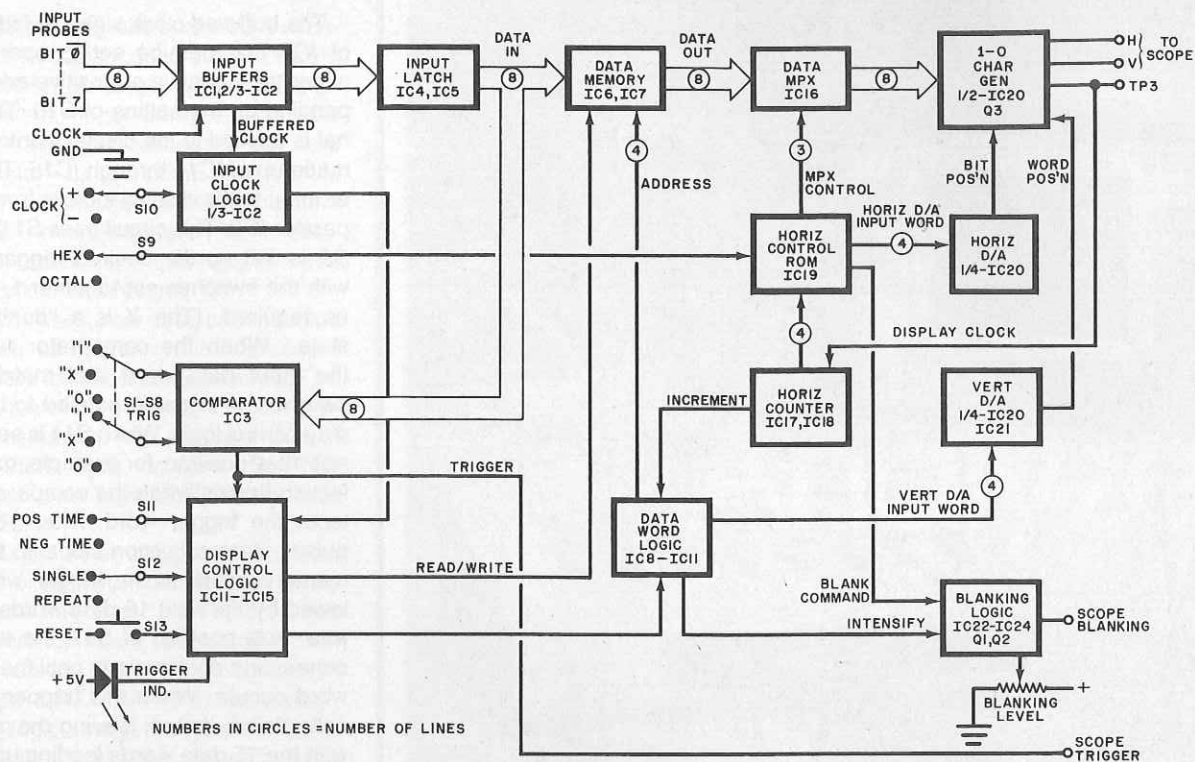


Fig. 2. Block diagram of analyzer shows basic signal routing.

**PARTS LIST**

C1—2200- $\mu$ F, 16-volt electrolytic capacitor  
 C2—220- $\mu$ F, 50-volt electrolytic capacitor  
 C3—10- $\mu$ F, 50-volt electrolytic capacitor  
 C4,C5—150-pF, 10% disc capacitor  
 C6—15-pF, 10% disc capacitor  
 C7,C8,C9,C10—0.1- $\mu$ F, 20% disc capacitor  
 C11—300-pF, 10% disc capacitor  
 C12—180-pF, 10% disc capacitor  
 C13—0.01- $\mu$ F, 20% disc capacitor  
 D1,D2,D3—1N4002 or similar rectifier diode  
 IC1,IC2—74LS14 Schmitt-trigger input hex inverter (Fairchild 15-V input only)  
 IC3—74S15 open-collector output triple three-input AND gate  
 IC4,IC5,IC9—74LS175 quad latch  
 IC6,IC7—7489 RAM (16 $\times$ 4)  
 IC8—74LS161 four-bit synchronous counter  
 IC10—74LS83 four-bit adder  
 IC11,IC12,IC22—7400 quad two-input NAND gate  
 IC13,IC14,IC18—74LS73 dual JK flip-flop (do not substitute)  
 IC15—7473 dual JK flip-flop (do not substitute)  
 IC16—74LS151 8-to-1 multiplexer  
 IC17—74LS90 decade counter  
 IC19—8223 256-bit open-collector output PROM, or similar  
 IC20—LM3900 quad current amplifier  
 IC21—7407 open-collector output hex buffer  
 IC23—74LS21 dual four-input AND gate  
 IC24—7406 open-collector output hex inverter  
 IC25—LM309K 5-volt regulator  
 J1 through J4—UG-625 BNC connector

LED1—Light-emitting diode (any color)  
 Q1,Q3—2N3904 silicon transistor  
 Q2—2N3905 silicon transistor  
 The following resistors 1/4 watt, 5%:  
 R1 through R27—4700 ohms  
 R28—3300 ohms  
 R29—470 ohms  
 R30—1000 ohms  
 R31,R32,R33—8200 ohms  
 R34,R35,R36—2700 ohms  
 R37—1800 ohms  
 R38—2000 ohms  
 R39,R40—33,000 ohms  
 R41,R42—56,000 ohms  
 R43,R44,R45—22,000 ohms  
 R46,R47—24,000 ohms  
 R48,R49—130,000 ohms  
 R51,R52—180 ohms  
 R53—47,000 ohms  
 R54,R55—11,000 ohms  
 The following resistors 1/4-watt, 2% tolerance:  
 R56—4700 ohms  
 R57—2400 ohms  
 R58—5100 ohms  
 R59—2700 ohms  
 R50—5000-ohm trimmer potentiometer (Spectrol 43P502 or similar)  
 S1 through S8—double-pole 3-position pc-mounted switch  
 S9 through S12—dpdt pc-mounted switch  
 S13—momentary-action dpst pc-mounted switch  
 S14—spst switch (panel mount)  
 T1—dual-winding power transformer with 16-volt CT and 22-volt winding

Misc.—Line cord, strain relief, mounting hardware, 3 feet of Spectra-Strip multicolored flat ribbon cable (26 gauge), 16-pin DIP socket, 16-pin flat ribbon DIP plug, heat sink for voltage regulator, hookup wire, solder, suitable case and mounting brackets, probe tip connectors, etc.

Note: The following items are available from Paratronics, Inc., Dept. 100, Los Gatos, CA 95030: Complete kit of parts, No. LA-100KIT, with tested IC's, power supply, pc board, case, and manual for \$189.00. For separate parts: drilled double-sided printed circuit board, No. LA-100 PC, \$29.95; programmed horizontal control ROM, No. LA-100ROM, \$15.95; power supply, No. LA-100PS, \$39.95; complete set of switches, connectors, hardware and data probes, No. LA-100HW, \$39.95; Case, No. LA-100CASE, \$39.95. Comprehensive applications and assembly manual, LA-100MAN \$4.95. Please add 5% to above items for shipping and handling within U.S., 10% outside the U.S. California residents, add 6% sales tax.

Free copies of etching and drilling guides for the pc board, components-placement diagram, and horizontal control PROM programming information are available on request by sending a self-addressed stamped 9"  $\times$  12" envelope with 26¢ postage to: POPULAR ELECTRONICS, Dept. LA, One Park Ave., New York, NY 10016.

gital/analog) and the IC20-IC21 vertical D/A circuits to write a 1 or 0 at the proper location on the CRT screen.

The horizontal D/A circuit receives its 4-bit data word from the horizontal con-

trol ROM, which receives its address data from the horizontal counter made up of IC17 and IC18. It is the incrementing of the horizontal counter that causes the beam to move from right to left

across the face of the CRT as the data word is written.

When the last bit is displayed, horizontal counter IC17-IC18 "rolls over" to 0 and sends the increment signal to

data word logic IC8 through IC11. This causes the address of the data memory to advance to the next word location and simultaneously sends a command to the vertical D/A converter that causes the CRT beam to move down one row in preparation for display of the next word. This process continues until all sixteen of the words of interest have been written on the CRT screen.

If S12 is set to the SINGLE mode, the display control logic prevents the data memory from collecting new input data so that the same information is written on the CRT screen. The writing speed is fast enough so that a flicker-free "snapshot" of the memory contents is dis-

played. This snapshot will remain on the screen until the RESET switch S13 is operated, at which time the TRIGGER LED comes on and the analyzer is armed to "capture" another 16-word data set. When S12 is in the REPEAT mode, the display control logic provides an automatic reset signal after the display of each 16-word truth table.

Blanking between bits is provided by the remaining bit of the horizontal control ROM. This ROM performs three separate functions: control of the data multiplexer, control of the horizontal D/A converter, and blanking control. This use of a ROM as a controller is called "microprogramming," an efficient design

technique used in a number of high-level computers. An "intensify" command from the data-word logic permits the trigger word to appear brighter than the other data words on the CRT screen.

The trigger pulse generated by comparator IC3 occurs each time the trigger word appears. The resultant output pulse can be connected to the sync input of an oscilloscope anytime it is necessary to "look" at a specific signal in the circuit under test. This important feature is useful for troubleshooting equipment for glitches, timing, or intermittent problems that occur only during particular logic states.

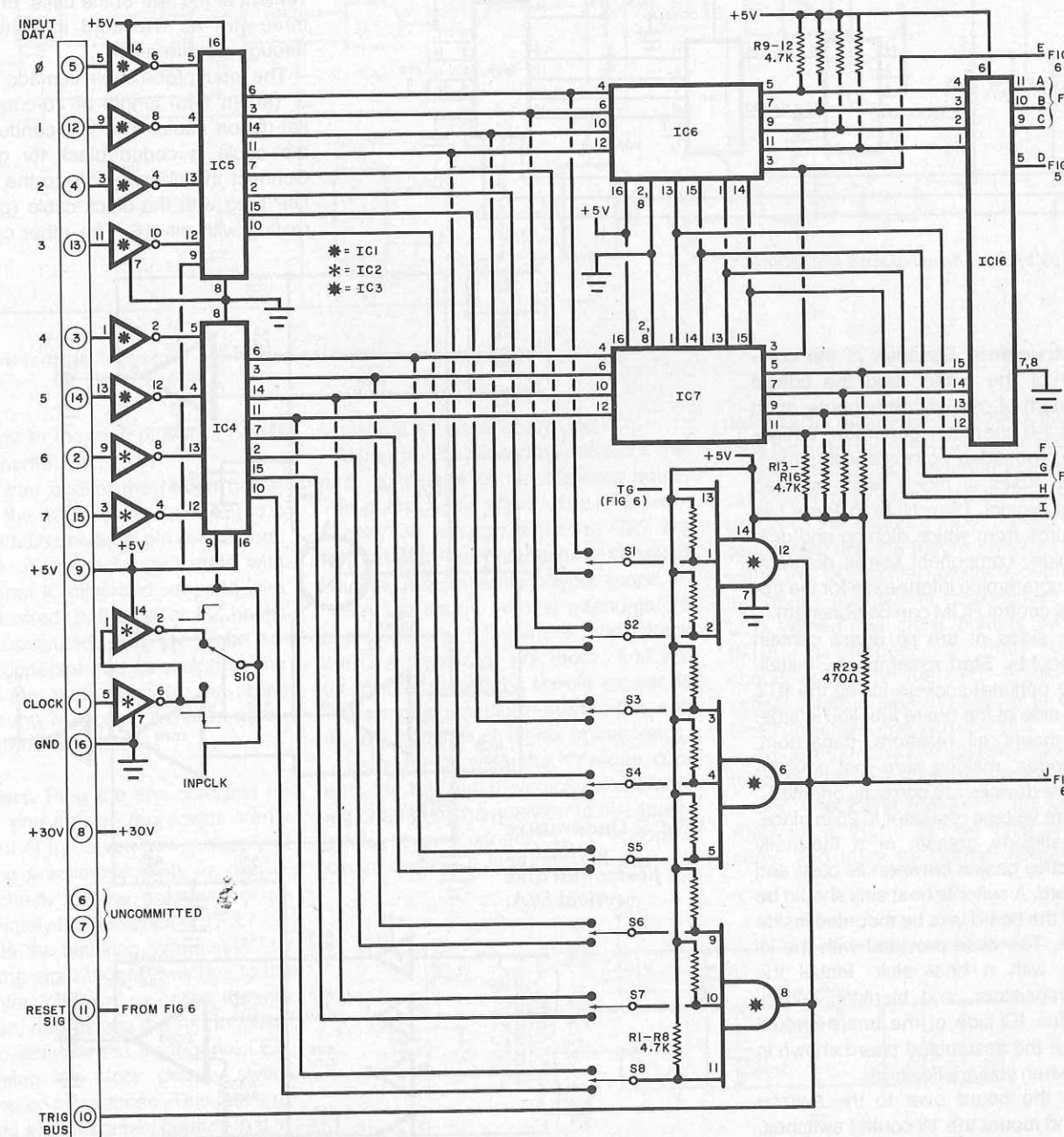


Fig. 3. Input buffers, trigger detector, memory, and data multiplexer.



For example, to see how the 4-bit address of the data memory sequentially changes during data collection, connect the first four data probes (BIT 0 through BIT 3) to pins 14, 13, 12, and 11 respectively, of IC8. The remaining four probes should remain unconnected. Connect the input clock probe to IC2 pin 10 (or TP3) and set the analyzer controls to HEX, REPEAT, NEG TIME, and the clock-polarity switch to the falling edge position. Set the first four trigger switches (S1 through S4) to 1111 and the last four to X. The selected trigger word should appear intensified at the bottom of the table, with the 15 prior binary address words listed in sequence above it.

#### LOGIC ANALYZER SPECIFICATIONS

**Trigger Word:** 0 to 8 bits wide; selected by eight 3-position switches; choose 0, 1, or X (don't care).

**Display Format:** Sixteen sequential 8-bit words arranged in an octal or hexadecimal truth table.

**Positive Time Display:** Trigger word intensified at top of truth table with next 15 data words listed below.

**Negative Time Display:** Trigger word intensified at bottom of truth table with prior 15 data words listed above.

**Single Mode:** Continuous display of one 16-word truth-table until RESET button is activated.

**Repeat Mode:** Display of sequential 16-word truth tables.

**Maximum Input Data Rate:** 8 million bytes/second.

**Input Clock:** Provides timing reference for input data; selectable positive or negative clock edge.

**Trigger Indicator:** LED on front panel indicates when trigger word has occurred.

**Trigger Output:** Auxiliary scope sync pulse; generated when trigger word occurs.

**Input Probes:** Constructed of color-coded flat-ribbon cable terminated in universal pin connectors.

**Input Load:** Inputs are buffered for minimal loading and have hysteresis for noise rejection.

**Power Supply:** +5 volts at 700 mA, +30 volts at 25 mA.

**Logic Family Compatibility:** TTL, DTL, RTL, MOS, CMOS, to 15-volt logic swing.

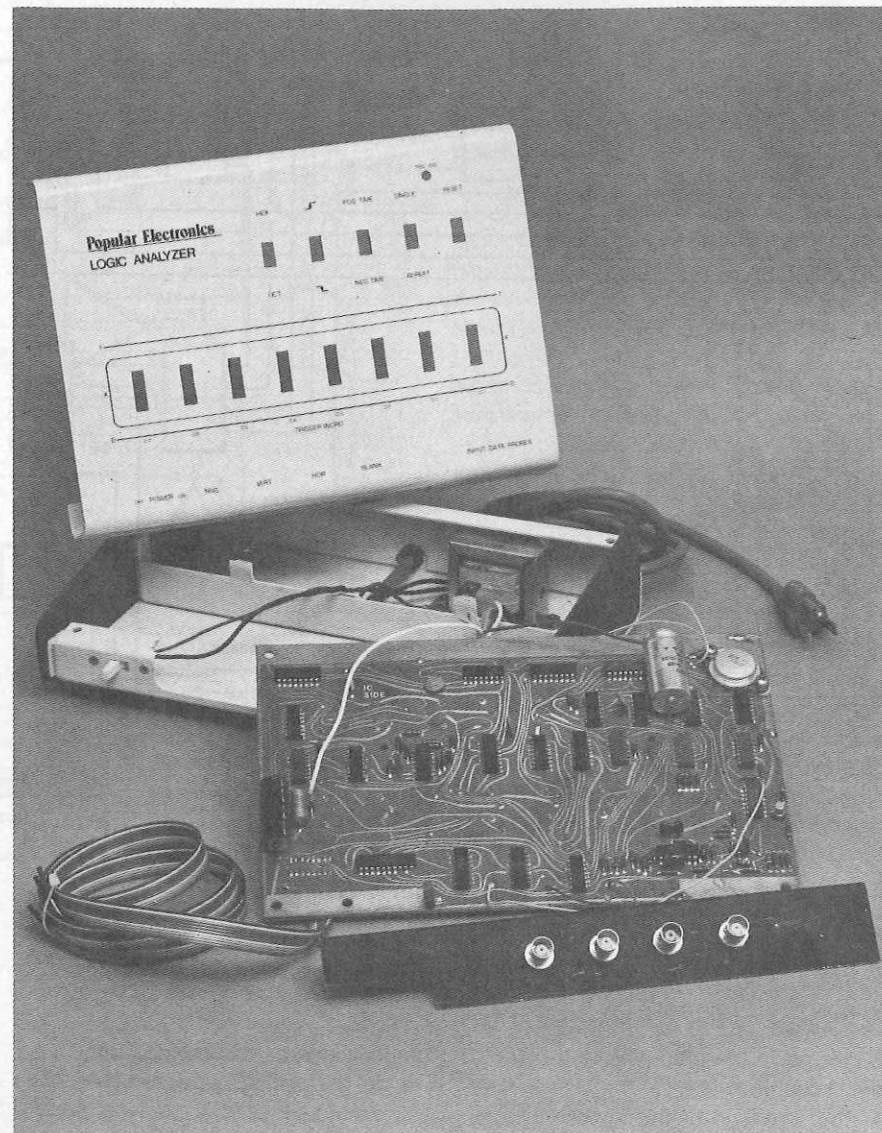


Fig. 8. Completed board and connector panel ready for assembly.

Continue to familiarize yourself with the operation of the analyzer by triggering from different address locations and changing the settings of the display control switches. The probes can be moved to other portions of the circuit, such as the horizontal counter, display-control logic, and the data-word logic.

You can couple the first four probes to the counter (7490 or similar) in any digital counter circuit to examine the operation of that circuit. In fact, the right side of the hex portion of the display in Fig. 1 shows the output of a "good" 4-bit counter while the left side shows the output of a counter whose MSB (most significant bit) is stuck at 0. Using this technique, you can follow the signals through almost any digital circuit and be able to "snapshot" any block of pulses so that they can be examined for faulty pulses.

The analyzer shows its flexibility when

used to check a computer or program. The octal portion of Fig. 1 shows the steps of a typical 8080 ADD and STORE program leading up to a branch instruction. The trigger word 00 000 001 is the branch address and is intensified at the bottom of the display.

**In Closing.** The Logic Analyzer we have described can be used for all types of testing and troubleshooting of digital circuits and systems. However, its true flexibility is revealed when the instrument is used for testing and troubleshooting digital-computer and other time-dependent circuits and systems. What makes our Logic Analyzer particularly attractive is its relatively low price. Used as an accessory to an existing oscilloscope and built from scratch, it costs only a fraction of commercially made logic analyzers on the market. ◇

# NEW, PRACTICAL OP AMP CIRCUITS

BY SOL D. PRENSKY

## including a differential pc board tester

**AS WE WILL** learn from the two very useful circuit applications described here, the operational amplifier (or op amp) can be used in strikingly different ways.

**In-Circuit Current Testing.** Since an op amp is basically a differential amplifier, it can be used in a unique metering circuit to determine the presence of current flow in a conductor—and approximately the amount of cur-

rent—whether or not the conductor is a copper wire or a pc foil trace. This can be done without breaking the conductor.

Such a metering device can come in handy if you have a crowded pc board and you suspect one of the active elements (transistor, diode, or IC) is not working. Instead of risking pc board damage due to the heat required to remove the suspect semiconductor, or having to cut a trace to insert a meter, all you have to do is press a couple of

sharp probe tips to the copper trace at (for example) the supply bus, and see if that particular element is drawing current, and if the magnitude of the current is within specifications.

The circuit for the current tester is shown in Fig. 1 in two forms—depending on whether you want to use a low-level (1-volt) dc voltmeter or a current meter as the readout.

Operation is based on the fact that at room temperatures, all conductors have

Fig. 1. Op amp in (A) measures slight voltage differential between two probes, amplifies it, and drives dc voltmeter. Addition of another op amp in (B) permits driving ammeter.

